TOSHIBA Photocoupler GaAs IRed & Photo-Triac

# TLP525G,TLP525G-2,TLP525G-4

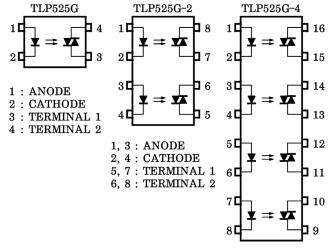
Triac Drive
Programmable Controllers
AC-Output Module
Solid State Relay

The TOSHIBA TLP525G, -2 and -4 consist of a photo–triac optically coupled to a gallium arsenide infrared emitting diode.

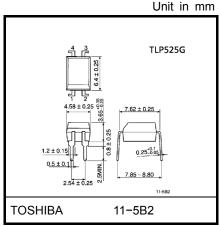
The TLP525G-2 offers two isolated channels in an eight lead plastic DIP package, while the TLP525G-4 provides four isolated channels in a sixteen lead plastic DIP package.

- Peak off-stage voltage: 400V (min.)
- Trigger LED current: 10mA (max.)
- Peak on-stage current: 2Apk (max.)
- Isolation voltage: 2500V<sub>rms</sub> (min.)
- UL recognized: File no.E67349

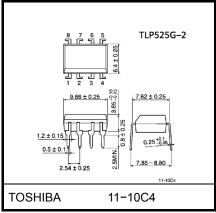
### Pin Configurations (top view)



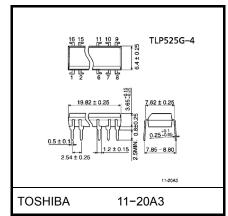
1, 3, 5, 7 : ANODE 2, 4, 6, 8 : CATHODE 9, 11, 13, 15 : TERMINAL 1 10, 12, 14, 16 : TERMINAL 2



Weight: 0.26g



Weight: 0.54g



Weight: 1.1g



#### Absolute Maximum Ratings (Ta = 25°C)

Characteristic				Ra		
			Symbol	TLP525G	TLP525G–2 TLP525G–4	Unit
LED	Forward current		lF	50	50	mA
	Forward current derating		I <sub>F</sub> / °C	–0.7 (Ta ≥ 53°C)	–0.5 (Ta ≥ 25°C)	mA / °C
	Pulse forward current		I <sub>FP</sub>	1 (100µs pulse, 100pps)		Α
	Reverse voltage		V <sub>R</sub>	5		V
	Junction temperature		Tj	125		°C
	Off-state output terminal voltage		$V_{DRM}$	400		V
	On-state RMS current	Ta = 25°C	l=	100	80	- mA
		Ta = 70°C	I <sub>T (RMS)</sub>	50	40	IIIA
Detector	On–state current derating (Ta≥25°C)		I <sub>T</sub> / °C	-1.1 -0.9		mA / °C
ľ	Peak on state current		I <sub>TP</sub>	2 (100µs pulse, 120pps)		Α
	Peak nonrepetitive surge current (P <sub>W</sub> = 10ms, DC = 10%)		I <sub>TSM</sub>	1.2		А
	Junction temperature		Tj	115		°C
Storage temperature range			T <sub>stg</sub>	<b>−55~125</b>		°C
Operating temperature range		T <sub>opr</sub>	-40~100		°C	
Lead soldering temperature			T <sub>sol</sub>	260 (10s)		°C
Isolation voltage (Note)		BVS	2500 (AC, 1min., R.H. ≤ 60%)		V <sub>rms</sub>	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note: Device considered a two terminal device: LED side pins shorted together and detector side pins shorted together.

#### **Recommended Operating Conditions**

Characteristic	Symbol	Min.	Тур.	Max.	Unit
Supply voltage	V <sub>AC</sub>	_	_	120	Vac
Forward current	l <sub>F</sub>	15	20	25	mA
Peak on-state current	I <sub>TP</sub>	_	_	1	Α
Operating temperature	T <sub>opr</sub>	-25	_	85	°C

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.



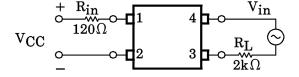
## **Individual Electrical Characteristics (Ta = 25°C)**

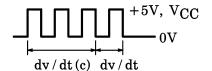
Characteristic		Symbol	Test Condition	Min.	Тур.	Max.	Unit
LED	Forward voltage	V <sub>F</sub>	I <sub>F</sub> = 10mA	1.0	1.15	1.3	V
	Reverse current	I <sub>R</sub>	V <sub>R</sub> = 5V	_	_	10	μΑ
	Capacitance	C <sub>T</sub>	V = 0, f = 1MHz	_	30	_	pF
	Peak off-state current	I <sub>DRM</sub>	V <sub>DRM</sub> = 400V	_	10	100	nA
	Peak on-state voltage	$V_{TM}$	I <sub>TM</sub> = 100mA	_	1.7	3.0	V
Detector	Holding current	lΗ	_	_	0.2		mA
	Critical rate of rise of off–state voltage	dv / dt	$V_{in} = 120V_{rms}$ , Ta = 85°C (Figure 1)	200	500	ı	V / µs
	Critical rate of rise of commutating voltage	dv / dt (c)	$V_{in}$ = 30 $V_{rms}$ , $I_T$ = 15 $mA$ (Figure 1)	_	0.2		V / µs

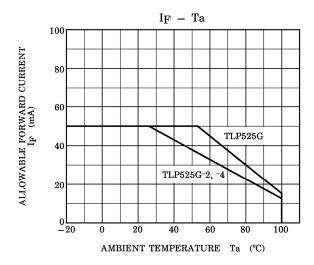
## **Coupled Electrical Characteristics (Ta = 25°C)**

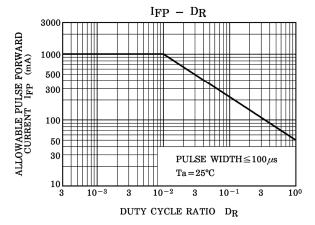
Characteristic	Symbol	Test Condition	Min.	Тур.	Max.	Unit
Trigger LED current	I <sub>FT</sub>	V <sub>T</sub> = 3V	_	5	10	mA
Capacitance input to output	CS	V <sub>S</sub> = 0, f = 1MHz	_	0.8	_	pF
Isolation resistance	R <sub>S</sub>	V <sub>S</sub> = 500V, R.H. ≤ 60%	5×10 <sup>10</sup>	10 <sup>14</sup>	_	Ω
	BVS	AC, 1 minute	2500	_	_	- Vrms
Isolation voltage		AC, 1 second, in oil	_	5000	_	
		DC, 1 minute, in oil	_	5000	_	Vdc

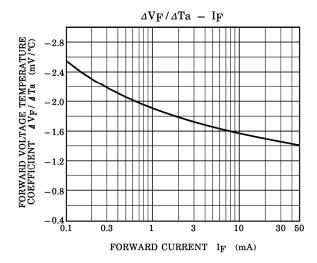
Fig.1 dv / dt Test Circuit

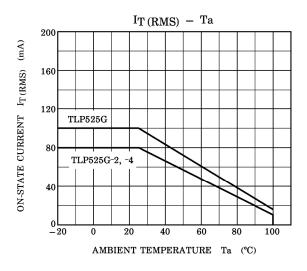


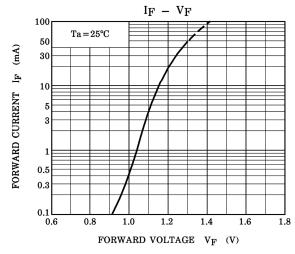


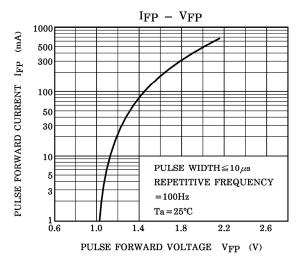


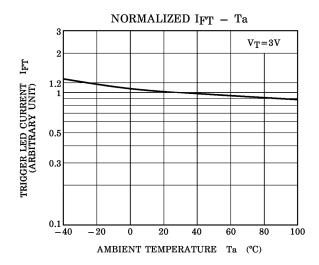


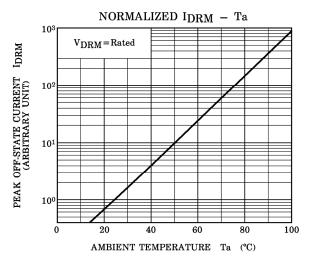


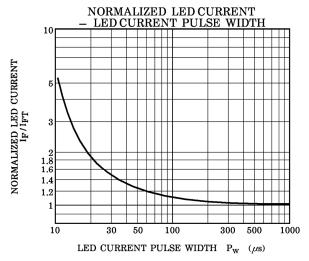


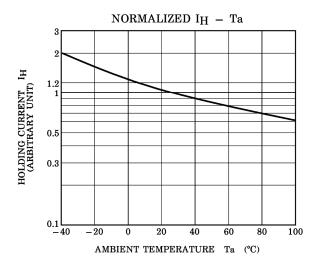


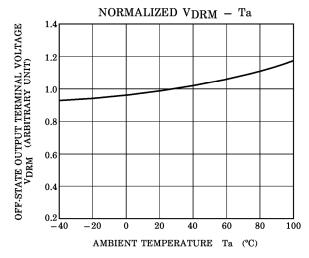












#### **RESTRICTIONS ON PRODUCT USE**

20070701-EN

- The information contained herein is subject to change without notice.
- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.
  In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc.
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in his document shall be made at the customer's own risk.
- The products described in this document shall not be used or embedded to any downstream products of which manufacture, use and/or sale are prohibited under any applicable laws and regulations.
- The information contained herein is presented only as a guide for the applications of our products. No
  responsibility is assumed by TOSHIBA for any infringements of patents or other rights of the third parties which
  may result from its use. No license is granted by implication or otherwise under any patents or other rights of
  TOSHIBA or the third parties.
- GaAs(Gallium Arsenide) is used in this product. The dust or vapor is harmful to the human body. Do not break, cut, crush or dissolve chemically.
- Please contact your sales representative for product-by-product details in this document regarding RoHS
  compatibility. Please use these products in this document in compliance with all applicable laws and regulations
  that regulate the inclusion or use of controlled substances. Toshiba assumes no liability for damage or losses
  occurring as a result of noncompliance with applicable laws and regulations.

6 2007-10-01